Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/464,322	KWON ET AL.

Examiner

Chris C. Chu

Art Unit 2815

SEARCHED				
Class	Subclass	Date	Examiner	
257	E23.103, 706 & 707	4/26/2007	C.C.	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	•			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	4/26/2007	C.C.
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